

Notice of References Cited	Application/Control No. 10/802,887	Applicant(s)/Patent Under Reexamination TANAKA ET AL.	
	Examiner Mark A. Chapman	Art Unit 1756	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2006/0078815	04-2006	Ito et al.	430/109.4
*	B	US-5,409,794	04-1995	Ong, Beng S.	430/108.3
*	C	US-4,518,672	05-1985	Urawa et al.	430/108.21
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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	N					
	O					
	P					
	Q					
	R					
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	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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